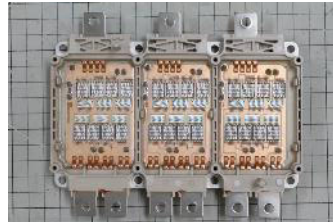


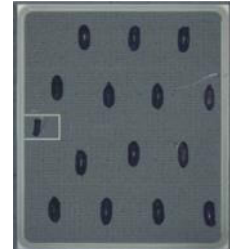
## **IGBT power module(750V): BYD (equipped in ATTO 3) BG820F08B14L5 Module & IGBT Structure Analysis Report**



<https://www.byd.com/jp/car/atto3>



Module appearance



IGBT die

### **Overview**

BYD, China's largest EV (electric vehicle) manufacturer began selling the ATTO 3 in China in February 2022. The ATTO 3 is equipped in a 58.56 kWh battery and can travel 485km.

It has also been on sale in Japan since January 2023 as an EV passenger car for the Japanese market.

This report is a structure analysis report that clarifies the details of the IGBT power module equipped in the "ATTO 3" inverter and the IGBT mounted in the module.

### **Product features**

- Product number: BG820F08B14L5 750V Si-IGBT IC = 820A
- Product release data: 2022 URL : <https://www.bjxchip.com/web/soft/bg820f08b14l5.pdf>
- Module equipped in ATTO 3 motor 150kW (system voltage 390V)
- IGBT uses 750V trench and field stop technology
- Module current capacity(Ic=500A :TF=65°C, Tvj=150°C, Ic=820A : TF=25°C, Tvj=175°C)
- The current density is 3.4 A/mm<sup>2</sup>.

### **Report Contents**

#### **1. Module structure analysis report (35 pages)**

- An external thermistor is used as the temperature detection element, and no temperature sensor diode is formed into the chips.
- Aluminum oxide DBC substrate is used for the insulating layer.

#### **2. IGBT structure analysis report (76 pages)**

- Trench type IGBT, 1-phase Si-IGBT(4 dies) and Si-FWD (3 dies).
- Cell pitch, trench width and depth are the same as those of Infineon EDT2 using a micro-trench process.
  - \* The trench bottom shape is distinctive. (This is confirmed in products of Chinese manufacturers)
- Due to issues with the size of the contact diameter and trench width, electrode extraction pads are used.

### **Report price**

**Delivered one week after order placement.**

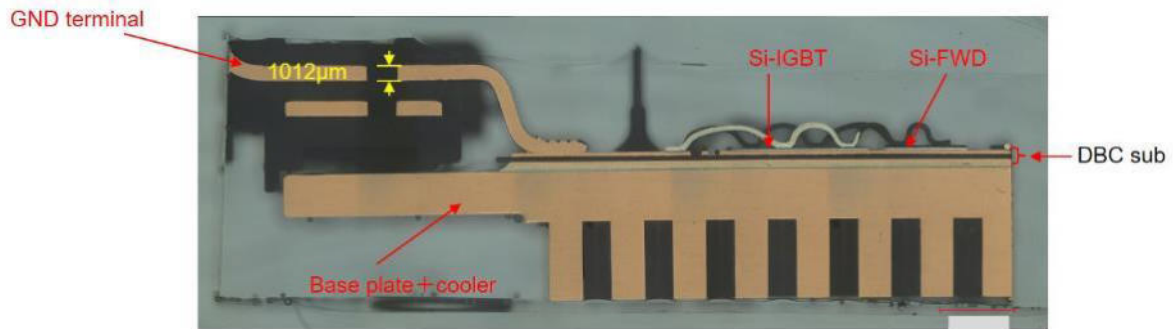
**Please contact us for report pricing.**

# 1. Module structure analysis report

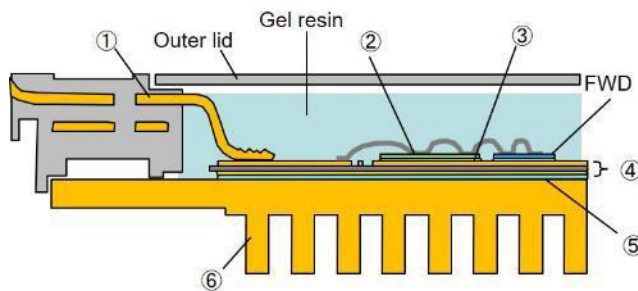
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## Excerpt from Module structure analysis report



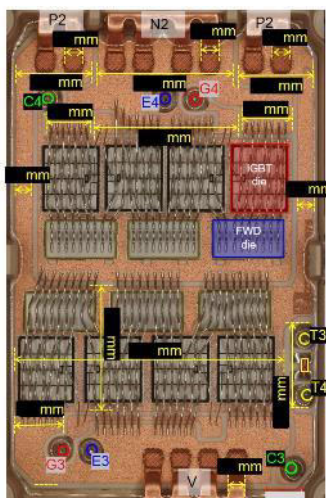
**Module cross-sectional OM image**



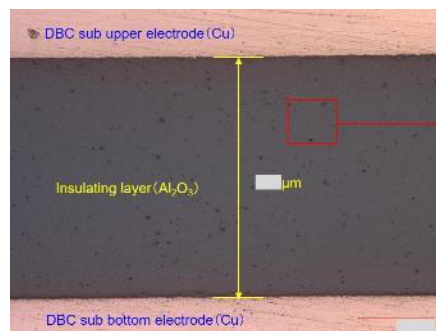
**Module cross-sectional structure image**

Number	Measurement points	Length measurement	Materials
1	Output terminal	3715μm	Cu
2	SI-IGBT		
2-1	Bonding wire	4475μm	Al
2-2	Protective film	714~8.7μm	SiO <sub>2</sub>
2-3	Substrate	14μm	Si
2-4	Backside metal-1	14μm	AlSi
2-5	Backside metal-2	14μm	Ti
2-6	Backside metal-3	14μm	V
3	Die attach(IGBT)	20.5μm	Solder
4	DBC sub		
4-1	DBC upper electrode	28μm	Cu
4-2	Insulating substrate	81.5μm	AlN/Al <sub>2</sub> O <sub>3</sub>
4-3	DBC bottom electrode	28.5μm	Cu
5	Solder	113μm	Solder
6	Cooler	2715μm	
6-1	Ni plating layer	1.5μm	Ni
6-2	Ni-P plating layer	0.2μm	Ni-P
6-3	Base plate	144μm	Cu
6-4	Cooling pin	1.08μm	Cu
7	Case		CO <sub>2</sub> Laser Welding

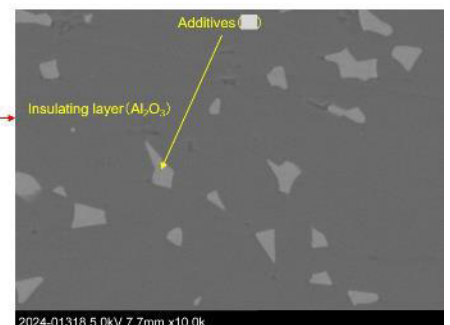
**Table: Module structure summary**



**Module internal layout**



**OM image**



**SEM image**

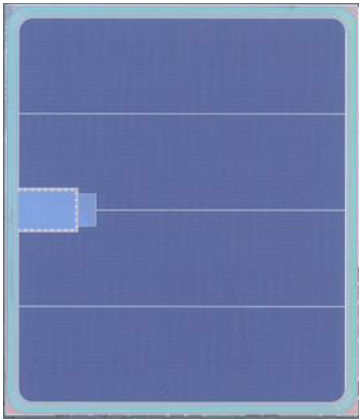
**DBC substrate insulating layer**

## 2. IGBT structure analysis report

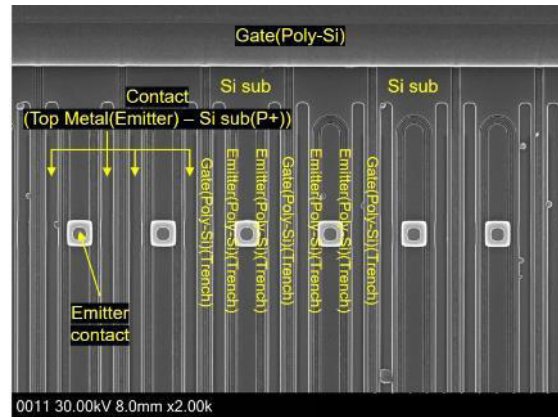
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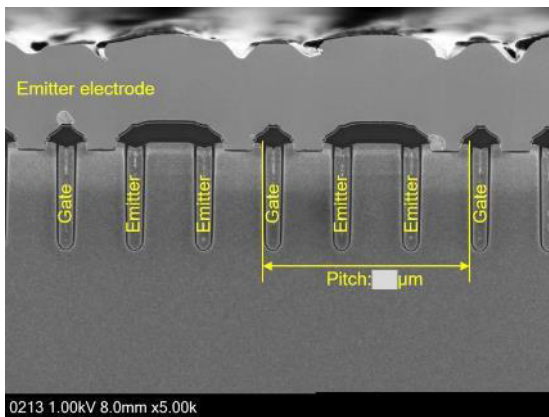
## Excerpt from IGBT structure analysis report



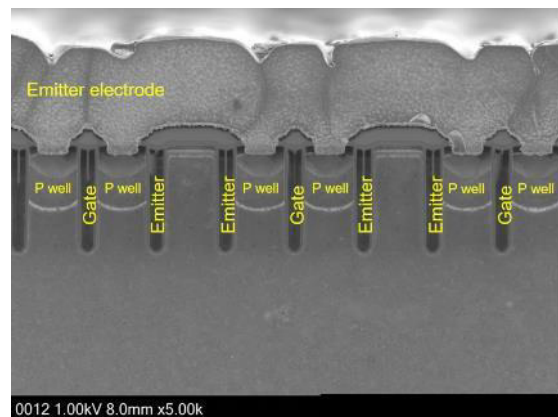
Si IGBT die (Poly-Si layer)



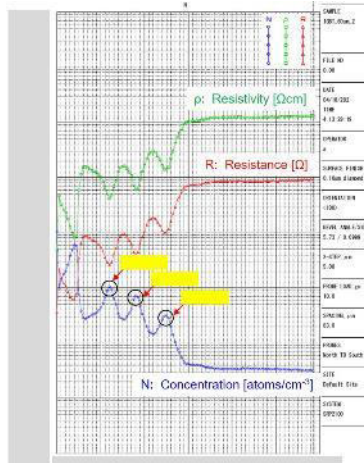
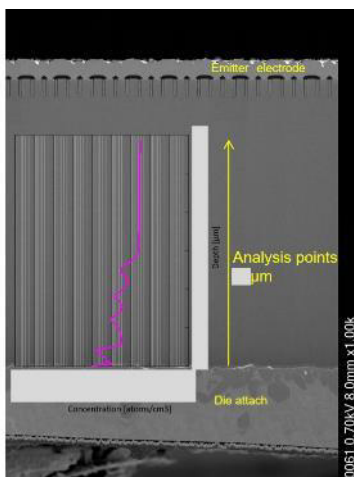
Plane SEM image of cell array (Poly-Si layer)



Cross-sectional SEM image of cell array



Cross-sectional SEM image of cell array (Stain etching)



SR analysis of IGBT backside

✂ The SR analysis results in this analysis report do not include data on the thickness and carrier concentration of the P+ Collector layer.